

ATTY DOCKET NO.

2270-0042

APPLICATION NO

10/007,100

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Sakamoto et al.

FILING DATE

December 6, 2001

GROUP

2633

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DS	A01	6,275,314	08/14/01	Ishikawa et al.	—	—	—
	A02	6,252,688	06/26/01	Ishikawa et al.	—	—	—
	A03	6,252,687	06/26/01	Ishikawa et al.	—	—	—
	A04	6,243,176	06/05/01	Ishikawa et al.	—	—	—
	A05	5,696,614	12/09/97	Ishikawa et al.	—	—	—
	A06	5,636,046	06/03/97	Ishikawa et al.	—	—	—
	A07	5,612,807	03/18/97	Ishikawa et al.	—	—	—
	A08	5,602,666	02/11/97	Ishikawa et al.	—	—	—
	A09	5,559,910	09/24/96	Taga et al.	—	—	—
	A10	5,410,624	04/25/95	Morkel	—	—	—
	A11	20010028489	10/11/01	Ishikawa et al.	—	—	—
DS	A12	20010022676	09/20/01	Ishikawa et al.	—	—	—

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
DS	B01	JP 2003179550	06/27/03	Japan				X
	B02	JP 3396441	04/14/03	Japan				X
	B03	JP 3396270	04/14/03	Japan				X
	B04	JP 11317705	11/16/99	Japan				X
	B05	JP 11313045	11/09/99	Japan				X
	B06	JP 7336301	12/22/95	Japan				X
	B07	JP 7107069	04/21/95	Japan				X
DS	B08	GB 2281670	03/08/95	Great Britain				X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	C01	
	C02	
	C03	

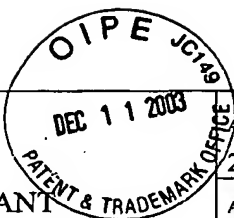
EXAMINER

Dalzid Singh

DATE CONSIDERED

12/16/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY DOCKET NO.	APPLICATION NO
	2270-042-999	10/007,100
	APPLICANT SAKAMOTO et al.	
	FILING DATE December 6, 2001	GROUP 2633

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DS	A01	JP 05-110517	04/30/93	Japanese Unexamined Patent Application w/ English Abstract	—	—	—
DS	A02	JP 07-38531	02/07/95	Japanese Unexamined Patent Application w/ English Abstract	—	—	—
DS	A03	JP 07-66779	03/10/95	Japanese Unexamined Patent Application w/ English Abstract	RECEIVED DEC 17 2003 Technology Center 2600		
DS	A04	JP 08-288930	11/01/96	Japanese Unexamined Patent Application w/ English Abstract			
	A05						
	A06						
	A07						
	A08						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	B01							
	B02							
	B03							
	B04							
	B05							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	C01	
	C02	
	C03	

EXAMINER Dalzid Singh	DATE CONSIDERED 12/16/04
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

ATTY DOCKET NO.

2270-0042

APPLICATION NO

10/0007,100

APPLICANT

Sakamoto et al.

FILING DATE

12/06/2001

GROUP

2633

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)



U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A01					
	A02					
	A03					
	A04					
	A05					
	A06					
	A07					
	A08					
	A09					

RECEIVED

JUN 16 2003

Technology Center 2600

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES NO
DS	B01	05-110517	4/30/93	Japan w/ English Abstract		X
DS	B02	06-090224	3/29/94	Japan w/ English Abstract		X
	B03					
	B04					
	B05					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

C01	
C02	
C03	

EXAMINER

Dalzid Singh

DATE CONSIDERED

12/16/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.